

Docket No.: H0782

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

*In re* Application of: David C. Newbury, et al. : Confirmation No.: 2638  
Serial No.: 10/791,130 : Art Unit: 2829  
Filed: 3/1/2004 : Examiner: Jermele M.  
Hollington  
For: TEST STRUCTURE AND :  
METHOD FOR FAILURE  
ANALYSIS OF SMALL  
CONTACTS IN  
INTEGRATED CIRCUIT  
TECHNOLOGY  
DEVELOPMENT

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**RESPONSE AFTER FINAL REJECTION  
UNDER 37 C.F.R. §1.116**

Sir:

The following Remarks are submitted under 37 C.F.R. §1.116 in response to the Office Action mailed March 20, 2006, following the format set forth under 37 CFR §1.121.

After this introductory section there are Remarks, starting on a separate page.

Reconsideration of the rejections is respectfully requested.

Please enter  
Jmt  
6/29/06